

# Claims

- [c1] 1. An arch type probe in the shape of a half circle arc, formed on and supported at one end thereof by a surface of a base plate of a probe card, having a first quarter circle arc portion which is supported at one end thereof by the base plate and a second quarter circle arc portion which is connected to the other end of the first quarter circle arc portion and a little shorter than the first quarter circle arc portion, wherein the top portion of the probe located at almost the center of the probe serves as a contact surface brought into contact with an electrode of the measurement objective.
- [c2] 2. An arch type probe according to claim 1, wherein a projected contact terminal is provided at the top portion thereof.
- [c3] 3. An arch type probe according to claim 1, wherein the distal end portion of the second quarter circle arc portion thereof is spherical.
- [c4] 4. An arch type probe according to claim 1, wherein coating is applied on the distal end surface of the distal end portion of the second quarter circle arc portion.

- [c5] 5. An arch type probe according to claim 1, in which a material necessary for raising a Young's modulus is incorporated.
- [c6] 6. A probe card being a sensing section of a semiconductor wafer measuring instrument, having a base plate mounted to a prober thereof and an arch type probe according to any of claims 1 to 5 formed on a surface of the base plate.
- [c7] 7. A probe card according to claim 6, wherein coating is applied on a portion of a surface of the base plate in contact with the distal end surface of the second quarter circle arc portion.
- [c8] 8. A probe card according to claim 6, wherein a reinforcing member with an elasticity higher than the arch type probe is provided integrally with the arch type probe on a surface thereof facing the base plate along the length direction.
- [c9] 9. A probe card according to claim 6, wherein a reinforcing member with an elasticity higher than the arch type probe is provided between the base plate and a surface of the arch type probe on the other side thereof from the top portion thereof.